TYPE	TYPICAL MAXIMUM CLOCK FREQUENCY	TYPICAL POWER DISSIPATION
′95A	36 MHz	195 mW
'LS95B	36 MHz	65 mW

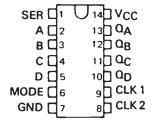
description

These 4-bit registers feature parallel and serial inputs, parallel outputs, mode control, and two clock inputs. The registers have three modes of operation:

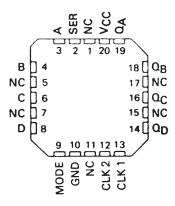
Parallel (broadside) load Shift right (the direction Q_{Δ} toward Q_{D}) Shift left (the direction QD toward QA)

Parallel loading is accomplished by applying the four bits of data and taking the mode control input high. The data is loaded into the associated flip-flops and appears at the outputs after the high-to-low transition of the clock-2 input. During loading, the entry of serial data is inhibited.

Shift right is accomplished on the high-to-low transition of clock 1 when the mode control is low; shift left is accomplished on the high-to-low transition of clock 2 when the mode control is high by connecting the output of each flip-flop to the parallel input of the previous flip-flop (QD to input C, etc.) and serial data is entered at input D. The clock input may be applied commonly to clock 1 and clock 2 if both modes can be clocked from the same source. Changes at the mode control input should normally be made while both clock inputs are low; however, conditions described in the last three lines of the function table will also ensure that register contents are protected. SN5495A, SN54LS95B . . . J OR W PACKAGE SN7495A . . . N PACKAGE SN74LS95B . . . D OR N PACKAGE (TOP VIEW)



SN54LS95B . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

FUNCTION TABLE

			INPUTS						OUT	PUTS	
MODE	CLO	CKS	CEDIAL		PARA	ALLEL			0.0	αc	α_{D}
CONTROL	2 (L)	1 (R)	SERIAL	Α	В	С	D	Q _A	ΩB	<u> </u>	α υ
Н	н	х	Х	Х	Х	Х	Х	QAO	α_{BO}	a_{C0}	σ^{DO}
н	+	х	x	a	b	С	d	а	b	С	d
H	1 +	X	×	QBt	Q _C †	QDt	d	Q _{Bn}	α_{Cn}	a_{Dn}	d
L	L	н	×	×	X	X	X	QAO	α_{BO}	a_{co}	O ^{DO}
L	×	4	н	x	X	X	X	Н	Q_{An}	QBn	a_{Cn}
L	×	1	L	×	X	X	X	L	Q_{An}	QBn	a_{Cn}
t	L	L	×	X	X	X	X	QAO	Q_{BO}	a_{co}	a_{D0}
1	L	L	×	x	X	X	X	QAO	Q_{BO}	σ_{CO}	a_{D0}
4	L	Н	×	x	X	×	X	QAO	Q _{BO}	σ_{CO}	σ^{DO}
†	н	L	×	x	X	X	X	QAO	Q_{BO}	σ_{CO}	σ_{DO}
†	н	Н	×	x	Х	X	X	QAO	Q _{BO}	a_{co}	a_{D0}

†Shifting left requires external connection of Q_B to A, Q_C to B, and Q_D to C. Serial data is entered at input D. H = high level (steady state), L = low level (steady state), X = irrelevant (any input, including transitions)

1 = transition from high to low level, 1 = transition from low to high level

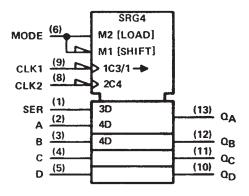
a, b, c, d = the level of steady-state input at inputs A, B, C, or D, respectively.

 Q_{A0} , Q_{B0} , Q_{C0} , Q_{D0} = the level of Q_{A} , Q_{B} , Q_{C} , or Q_{D} , respectively, before the indicated steady-state input conditions were established.

 Q_{An} , Q_{Bn} , Q_{Cn} , Q_{Dn} = the level of Q_{A} , Q_{B} , Q_{C} , or Q_{D} , respectively, before the most-recent \downarrow transition of the clock.

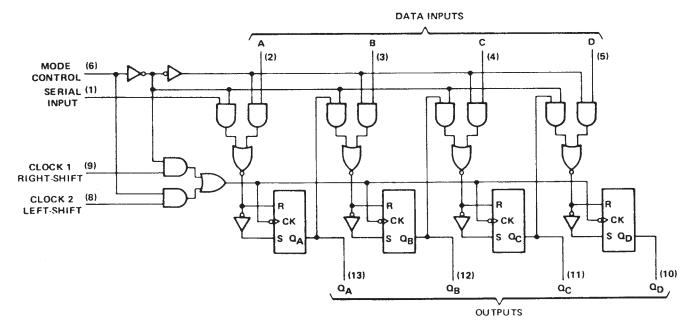


logic symbol†



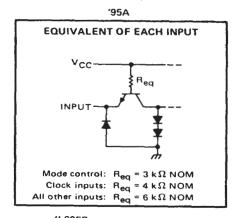
[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for D, J, N, and W packages.

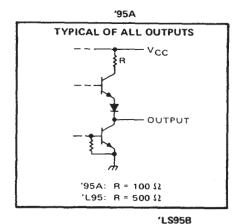
logic diagram (positive logic)

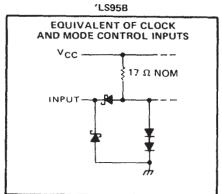


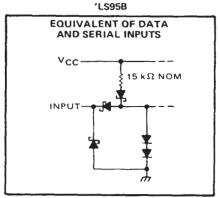


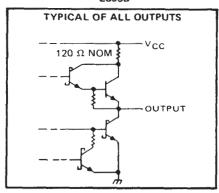
schematics of inputs and outputs











absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

	SN54'	SN54LS'	SN74'	SN74LS'	UNIT
Supply voltage, V _{CC} (see Note 1)	7	7	7	7	V
Input voltage	5.5	7	5.5	7	V
Interemitter voltage (see Note 2)	5.5		5.5		V
Operating free-air temperature range	- 55	- 55 to 125		to 70	°C
Storge temperature range	-65 to 150		- 65 to 150		°C

- NOTES: 1. Voltage values, except interemitter voltage, are with respect to network ground terminal.
 - 2. This is the voltage between two emitters of a multiple-emitter input transistor. This rating applies between the clock-2 input and the mode control input of the '95A.

recommended operating conditions

		SN5495A			SN7495A		
	MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}	4.5	5	5.5	4.75	5	5.25	٧
High-level output current, IOH			-800			-800	μΑ
Low-level output current, IOL			16			16	mA
Clock frequency, fclock	0		25	0		25	MHz
Width of clock pulse, tw(clock) (See Figure 1)	20			20			กร
Setup time, high-level or low-level data, t _{SU} (See Figure 1)	15			15			ns
Hold time, high-level or low-level data, th (See Figure 1)	0			0			ns
Time to enable clock 1, tenable 1 (See Figure 2)	15			15			ns
Time to enable clock 2 (See Figure 2)	15			15			กร
Time to inhibit clock 1, tinhibit 1 (See Figure 2)	5			5			ns
Time to inhibit clock 2, tinhibit 2 (See Figure 2)	5			5			ns
Operating free-air temperature, TA	55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER				SN5495A						
			TEST CONDITIONS [†]	MIN	TYP‡	MAX	MIN	TYP‡	MAX	UNIT
VIH	High-level input volta	ige		2			2			V
VIL	Low-level input volta	ge				0.8			0.8	٧
VIK	Input clamp voltage		V _{CC} = MIN, I _I = -12 mA	<u> </u>		-1.5			-1.5	V
			V _{CC} = MIN, V _{IH} = 2 V,	2.4	3.4		2.4	3.4		V
VOH	High-level output voltage		$V_{1L} = 0.8 \text{ V}, I_{OH} = -800 \mu\text{A}$	2.4	3.4		2.4	3.4		ľ
	Low-level output voltage		V _{CC} = MIN, V _{IH} = 2 V,			0.4		0.2	0.4	v
VOL			V _{1L} = 0.8 V, I _{OL} = 16 mA		0.2	0.4		0.2	0.4	
Ц	Input current at maximum input volta	age	V _{CC} = MAX, V _I = 5.5 V			1			1	mA
hн	High-level	Serial, A, B, C, D, Clock 1 or 2	V _{CC} = MAX, V ₁ = 2.4 V		-	40			40	μА
111	input current	Mode control	1			80			80	1
	Low-level	Serial, A, B, C, D,				-1.6			1.6	
HE	input current	Clock 1 or 2	V _{CC} = MAX, V _I = 0.4 V	-		-3.2	-		-3.2	mA
		Mode control					10			mA
los	Short-circuit output	current §	V _{CC} = MAX	-18		-57	-18		-57	
Icc	Supply current		V _{CC} = MAX, See Note 3		39	63	1	39	63	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f _{max} Maximum clock frequency	0 - 15 - 5 . D 400 0	25	36		MHz
tPLH Propagation delay time, low-to-high-level output from clock	C _L = 15 pF, R _L = 400Ω , See Figure 1		18	27	ns
tPHL Propagation delay time, high-to-low-level output from clock	See Figure 1		21	32	ns



 $^{^{\}ddagger}$ All typical values are at VCC = 5 V, TA = 25 °C.

[§] Not more than one output should be shorted at a time.

NOTE 3: ICC is measured with all outputs and serial input open; A, B, C, and D inputs grounded; mode control at 4.5 V; and a momentary 3 V, then ground, applied to both clock inputs.

recommended operating conditions

	SN	154 LS9	5B	SB SN74LS95B			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	ONT
Supply voltage, VCC	4.5	5	5.5	4.75	5	5.25	٧
High-level output current, IOH			-400			-400	μА
Low-level output current, IOL			4			8	mA
Clock frequency, fctock	0		25	0		25	MHz
Width of clock pulse, tw(clock) (see Figure 1)	20			20			ns
Setup time, high-level or low-level data, t _{su} (see Figure 1)	20	-		20			ns
Hold time, high-level or low-level data, th (see Figure 1)	20			10			ns
Time to enable clock 1, tenable 1 (see Figure 2)	20			20			ns
Time to enable clock 2, tenable 2 (see Figure 2)	20			20			ns
Time to inhibit clock 1, tinhibit 1 (see Figure 2)	20			20			ns
Time to inhibit clock 2, tinhibit 2 (see Figure 2)	20			20			ns
Operating free-air temperature, TA	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

			- 4	Sf	154LS9	58	SI	174LS9	5B	UNIT
	L Low-level input voltage K Input clamp voltage High-level output voltage	TEST CO	TEST CONDITIONS†		TYP [‡]	MAX	MIN	TYP [‡]	MAX	UNIT
ViH	High-level input voltage			2			2			V
VIL	Low-level input voltage					0.7			8.0	V
VIK	The second secon	V _{CC} = MIN,	$I_1 = -18 \text{ mA}$			-1.5			-1.5	V
	High-level output voltage	V _{CC} = MIN, V _{IL} = V _{IL} max,	V _{IH} = 2 V, I _{OH} = -400 μA	2.5	3.4		2.7	3.4		V
	Low-level output voltage	V _{CC} = MIN,	IOL = 4 mA		0.25	0.4		0.25	0.4	,
VOL		V _{IH} = 2 V, V _{IL} = V _{IL} max	1 _{OL} = 8 mA					0.35	0.5	Ľ
l ₁	Input current at maximum input voltage	V _{CC} = MAX,	V ₁ = 7 V			0.1			0.1	mA
чн	High-level input current	V _{CC} = MAX,	V ₁ = 2.7 V			20			20	μА
IJĹ	Low-level	V _{CC} = MAX,	V ₁ = 0.4 V			-0.4			-0.4	mA
los	Short-circuit output current \$	V _{CC} = MAX		-20		-100	-20		-100	mA
Icc	Supply current	V _{CC} = MAX,	See Note 3		13	21		13	21	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f _{max} Maximum clock frequency	$C_1 = 15 pF$, $R_1 = 2 k\Omega$.	25	36		MHz
tp_H Propagation delay time, low-to-high-level output from clock	See Figure 1		18	27	ns
tpHL Propagation delay time, high-to-low-level output from clock			21	32	ns

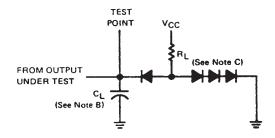


[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25 ^{\circ}\text{C}$.

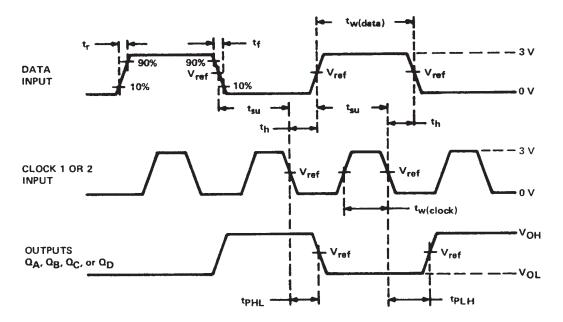
[§] Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.

NOTE 3: ICC is measured with all outputs and serial input open; A, B, C, and D inputs grounded; mode control at 4.5 V; and a momentary 3 V, then ground, applied to both clock inputs.

PARAMETER MEASUREMENT INFORMATION



LOAD CIRCUIT

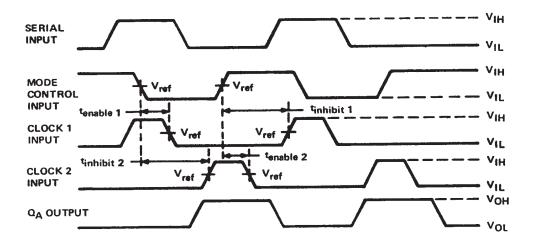


- NOTES: A. Input pulses are supplied by a generator having the following characteristics: $t_r \le 10$ ns, $t_f \le 10$ ns, and $Z_{out} \approx 50 \Omega$. For the data pulse generator, PRR = 500 kHz; for the clock pulse generator, PRR = 1 MHz. When testing f_{max} , vary PRR. For '95A, $t_{w(data)} \ge 20$ ns, $t_{w(clock)} \ge 15$ ns. For 'LS95B, $t_{w(data)} \ge 20$ ns, $t_{w(clock)} \ge 15$ ns.
 - B. C_L includes probe and jig capacitance.
 - C. All diodes are 1N3064 equivalent.
 - D. For '95A, $V_{ref} = 1.5 \text{ V}$; for 'LS95B, $V_{ref} = 1.3 \text{ V}$.

VOLTAGE WAVEFORMS
FIGURE 1-SWITCHING TIMES



PARAMETER MEASUREMENT INFORMATION



NOTES: A. Input is at a low level.

B. For '95A, $V_{ref} = 1.5 \text{ V}$; for 'LS958, $V_{ref} = 1.3 \text{ V}$.

VOLTAGE WAVEFORMS
FIGURE 2-CLOCK ENABLE/INHIBIT TIMES



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